## A versatile nanoreactor for complementary in situ X-ray and electron microscopy studies in catalysis and materials science

Authors

Yakub Fam<sup>a</sup>, Thomas L. Sheppard<sup>ab\*</sup>, Johannes Becher<sup>a</sup>, Dennis Scherhaufer<sup>c</sup>, Heinz
Lambach<sup>c</sup>, Satishkumar Kulkarni<sup>d</sup>, Thomas F. Keller<sup>de</sup>, Arne Wittstock<sup>f</sup>, Felix Wittwer<sup>de</sup>,
Martin Seyrich<sup>de</sup>, Dennis Brueckner<sup>deg</sup>, Maik Kahnt<sup>de</sup>, Andreas Schropp<sup>d</sup>, Andreas Stierle<sup>de</sup>,
Christian G. Schroer<sup>de</sup> and Jan-Dierk Grunwaldt<sup>ab\*</sup>
<sup>a</sup>Institute for Chemical Technology and Polymer Chemistry, Karlsruhe Institute of Technology,
Engesserstr. 20, Karlsruhe, Baden Württemberg, 76131, Germany
<sup>b</sup>Institute of Catalysis Research and Technology, Karlsruhe Institute of Technology, Hermann-von-Helmholtz Platz 1, Eggenstein-Leopoldshafen, Baden Württemberg, 76344, Germany
<sup>c</sup>Institute for Micro Process Engineering, Karlsruhe Institute of Technology, Hermann-von-Helmholtz
Platz 1, Eggenstein-Leopoldshafen, Baden Württemberg, 76344, Germany
<sup>d</sup> Deutsches Elektronen-Synchrotron DESY, Notkestraße 85, Hamburg, 22607, Germany
<sup>e</sup>Department Physik, Universität Hamburg, Luruper Chaussee 149, Hamburg, 22761, Germany
<sup>f</sup>Institute of Applied and Physical Chemistry, Ruhr-University Bochum, Universitätsstr. 150, Bochum, 44801, Germany

Correspondence email: thomas.sheppard@kit.edu; grunwaldt@kit.edu

**Synopsis** A series of nanoreactors have been developed for complementary *in situ* X-ray and electron microscopy. The setup was utilized to monitor thermal annealing processes of porous materials under controlled atmospheres with hard X-ray ptychography.

**Abstract** Two *in situ* 'nanoreactors' for high resolution imaging of catalysts have been designed and applied at the hard X-ray nanoprobe endstation at beamline P06 of the PETRA III synchrotron radiation source. The reactors house samples supported on commercial microchips, and were applied for complementary hard X-ray ptychography (22 nm spatial resolution) and transmission electron microscopy, with additional X-ray fluorescence measurements. The reactors allow pressures of 100 kPa and temperatures of up to 1573 K, offering a wide range of conditions relevant for catalysis. Ptychographic tomography was demonstrated at limited tilting angles of at least  $\pm 35^{\circ}$  within the reactors, and  $\pm 65^{\circ}$  on the naked sample holders. Two case studies were selected to demonstrate the functionality of the reactors: (i) annealing of hierarchical nanoporous gold up to 923 K under inert He environment; (ii) acquisition of a ptychographic projection series at  $\pm 35^{\circ}$  of a hierarchically-structured

1

macroporous zeolite sample under ambient conditions. The reactors are shown to be a flexible and modular platform for *in situ* studies in catalysis and materials science which may be adapted for a range of sample and experiment types, opening new characterization pathways in correlative multimodal *in situ* analysis of functional materials at work. The cells will presently be made available for all interested users of beamline P06 at PETRA III.

Keywords: in situ; ptychography; X-ray microscopy; electron microscopy; catalysis.

#### 1. Introduction

In the study of heterogeneous catalysis, derivation of structure-activity relationships is critical to unravel the role of catalysts in chemical processes as well as to improve their performance and stability. Since catalyst structure evolves with the chemical environment present, studies under working conditions (*in situ*) and with simultaneous acquisition of catalytic activity data (*operando*), are of high importance (Topsøe, 2003; Bañares, 2005; Grunwaldt & Clausen, 2002; Weckhuysen, 2002). As catalysts often possess a complex structure, another cornerstone in catalysis research is the collection of spatially-resolved or local structural information. This is often achieved using imaging techniques such as electron or X-ray microscopy or a combination of these (Beale et al., 2010; Frenkel & Van Bokhoven, 2014), especially if information at different length scales is required for a comprehensive understanding of the catalyst (Weckhuysen, 2009; Beale et al., 2010; Grunwaldt et al., 2013). Although electron microscopy and soft X-ray microscopy offer superior spatial resolution (De Smit et al., 2008; Thomas & Hernandez-Garrido, 2009) for in situ measurements on real catalysts (e.g. powders, pellets), hard X-rays may arguably be regarded as the most suitable probe. Hard X-rays may be applied on µm to mm sized samples under more practical working conditions, e.g. 100 kPa or elevated pressures, compared to soft X-ray or electron microscopy (Grunwaldt & Schroer, 2010; Buurmans & Weckhuysen, 2012). At the same time, development of hard X-ray focusing optics is constantly progressing towards beam spot sizes and spatial resolutions comparable to those soft Xrays and electron microscopy (Schroer et al., 2017; Seiboth et al., 2017). In terms of spatial resolution, scanning coherent X-ray diffraction imaging, also known as X-ray ptychography (XRP), has been the main X-ray imaging technique to make a significant breakthrough, i.e. 5 nm for soft Xrays (Shapiro et al., 2014) and 10 nm for hard X-rays (Vila-Comamala et al., 2011; Schropp et al., 2012). Ptychography employs a coherent X-ray beam to scan over the sample, while recording farfield diffraction patterns with a partial overlap between adjacent points in real space. By using iterative phase retrieval algorithms, the overlapping diffraction patterns are then reconstructed into real space images. The use of highly coherent flux and the absence of focusing optics between the sample and detector effectively means that the spatial resolution of ptychography is not limited by the beam spot size, offering excellent potential for high resolution imaging (Guizar-Sicairos et al., 2015;

2

Schropp *et al.*, 2012). However, combining *in situ* measurements with spatially-resolved microscopy at the nanometer scale, including complementary characterization of identical samples by multiple techniques, is a challenging but highly valuable prospect (Weker *et al.*, 2016). While XRP is often used *ex situ* for many applications (Thibault *et al.*, 2008; Hoppe *et al.*, 2013; Piazza *et al.*, 2014; Zhu *et al.*, 2015; Wise *et al.*, 2016; Sala *et al.*, 2018), *in situ* imaging modes, particularly on catalyst materials where accurate control of temperature and gas conditions are essential, have not been widely explored outside of a few pioneering works (Høydalsvik *et al.*, 2014; Van Riessen *et al.*, 2017), including those from our group (Baier, Damsgaard, *et al.*, 2016; Baier, Wittstock, *et al.*, 2016; Baier *et al.*, 2017). Nevertheless, these studies still leave much room for improvement in terms of spatial resolution, detection of possible reaction products, and the application of complementary imaging modes (e.g. transmission electron microscopy (TEM), X-ray fluorescence (XRF)), as discussed below. An outlook on the experimental potential of *in situ* X-ray imaging by a range of methods including XRP was recently outlined in literature (Weker *et al.*, 2016).

One of the first *in situ* XRP studies on catalytic materials was carried out to probe lithium zirconate for CO<sub>2</sub> capture applications. A spatial resolution of 200 nm (Høydalsvik et al., 2014) was achieved, although the experiment was performed in a large gas-filled enclosure, rather than a closed *in situ* cell with controlled internal volume and gas atmosphere. Simultaneous use of in situ XRP and XRF nanospectroscopy was later shown to monitor morphological changes and elemental distribution during thermal curing of geopolymers on sub-micrometer length scales, though the experimental apparatus was not fully discussed (Van Riessen et al., 2017). We previously described the design and application of closed in situ cells based on micro-electron-mechanical systems (MEMS) chips for XRP of catalyst materials, and studied morphological changes of colloidal gold nanoparticles and nanoporous gold catalysts during thermal annealing under specific gas atmospheres with spatial resolutions down to 20 nm (Baier, Damsgaard, et al., 2016; Baier, Wittstock, et al., 2016). Another application was to study the stability of a CuO/ZnO/Al<sub>2</sub>O<sub>3</sub>@ZSM-5 core@shell material under reducing and oxidizing conditions, obtaining 30 nm spatial resolution (Baier et al., 2017). Notably, the previous *in situ* cells could also be used for complementary electron microscopy on identical sample regions. However, the aforementioned setup (Baier, Damsgaard, et al., 2016) possessed some limitations. Apart from a relatively bulky design, high mass (>100 g) and large internal volume, it was not possible to perform complementary XRF imaging or quantify products for operando studies, while sample heating was controlled indirectly via infra-red (IR) thermography. Hence, further improvements are required particularly with regard to sample stability, mechanical vibrations, and experimental control of temperature. Recently, an alternative cell based on MEMS chips was reported for 2D nanofluorescence spectroscopy of Fischer-Tropsch synthesis catalysts under in situ conditions (van Ravenhorst et al., 2018). However, this was optimized for scanning transmission X-ray microscopy (STXM) which is strictly limited by the beam spot size, rather than ptychography which

can offer superior spatial resolution which is not dependent of the beam spot size (Schropp *et al.*, 2012; Guizar-Sicairos *et al.*, 2015).

In this study, we present a series of new and improved *in situ* cells based on MEMS chips for complementary X-ray nanoimaging and spectroscopy measurements of catalysts and other functional materials using synchrotron radiation. The cells were designed to allow high resolution imaging in 2D (2G cell) and tomographic imaging in 3D (3G cell) with limited rotational angles, where 3D volume data may potentially be reconstructed via missing-wedge tomography algorithms without the need to perform full 180° rotation. In both cases, the cells can operate under *in situ* conditions, i.e. with controlled temperature up to 1573 K and gas environments up to 100 kPa. Hence, the design principles and main features of the 2G and 3G cells are firstly introduced, including discussion on improvement from previous cell designs. Next, experimental case studies are introduced with the newly commissioned cells. 2D XRP was used to monitor thermal sintering and annealing of monolithic nanoporous gold (np-Au) as a bulk catalyst material. A related example of complementary XRP and XRF mapping of 50 nm gold colloids during sintering is shown in the Supporting Information. Furthermore, to demonstrate the possibility of performing tomographic measurements in the cells, a hierarchical micro/macroporous zeolite particle was investigated under a limited rotational angle series of  $\pm 35^\circ$ , with the possibility to extend this to  $\pm 65^\circ$  depending on experimental needs.

#### 2. Experimental

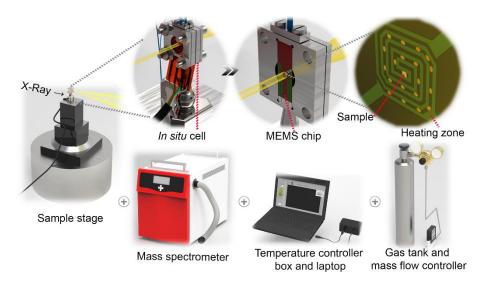
#### 2.1. Design of the in situ cells and experimental setup

The *in situ* cells used in this study were designed specifically for use at the hard X-ray nanoprobe endstation at beamline P06 at the PETRA III synchrotron radiation source (Hamburg, DE), although in principle the design is flexible enough for incorporation at similar Nanoprobe beamlines. Two *in situ* cells with specific target functions were commissioned:

- an *in situ* cell for high-resolution *in situ* XRP in 2D, with complementary XRF and/or large angle X-ray diffraction (XRD) mapping, denoted as '2G cell'.
- an *in situ* cell allowing limited-angle 3D *in situ* ptychographic X-ray computed tomography (PXCT) in addition to standard 2D XRP, denoted as '3G cell'.

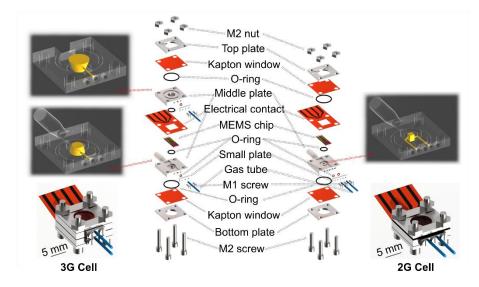
Both cells are based on modular design principles and can be interchangeably integrated into the same setup (Figure 1). For accurate temperature control, a 'Digiheater' temperature controller box and software are used (DENSsolutions, Delft, NL), with printed electrical contacts to interface with the MEMS chip. Mass flow controllers (Bronkhorst High-Tech B.V., Ruurlo, NL) provide accurate control of the gas environment, while a mass spectrometer (Thermostar, Pfeiffer Vacuum GmbH, Aßlar, DE) positioned at the reactor outlet allows for gas analysis. The cell is fixed in a standing

position on the beamline stage (Figure 1, top left), which includes lateral piezomotors for nanopositioning and a goniometer for optional center of rotation alignment. Within the cell, there is a 'Wildfire' MEMS chip (DENSsolutions, Delft, NL), on which samples are deposited on the center spiral-shaped sample area (Figure 1, top right). The sample area may be with or without silicon nitride (Si<sub>3</sub>N<sub>4</sub>) membranes, depending on the experimental requirements and the type of chip used. The operational range of the Wildfire chip is certified at 100 kPa pressure and up to 1373 K with Si<sub>3</sub>N<sub>4</sub> membranes, or 1573 K with through-hole chips. The heating zone is indicated by the spiral, but it has been proven to be well-localized within 0.5 mm from the center point. Since the MEMS chips have been commercially utilized for TEM, complementary TEM measurements may readily by performed along with *in situ* XRP and PXCT by simply removing the chip and placing it in an appropriate electron microscopy sample holder.



**Figure 1** Illustration of the *in situ* setup for 2D and 3D ptychography at the P06 nanoprobe endstation of PETRA III. Top - zooming in to the in situ cell; bottom - gas and temperature control infrastructure and product analytics.

Both the 2G and 3G cells have the same general configuration, where the top and bottom plates containing the MEMS chip are fixed between O-rings and Kapton films (Figure 2). Small side plates and O-rings provide gas tight sealing of the inlet/outlet gas tubes. Both cells have a similar arrangement for the electrical contact, in the form of a printed circuit (Au on Kapton) which should be positioned on top of the MEMS chip so that the four contact pads on each are well aligned. This electrical contact serves to deliver the current from the temperature controller box (power supply) to the MEMS chip, such that the chip can convert the electrical supply into heat based on the Joule-heating principle. The final similarity between the 2G and 3G cells comes from the small O-ring below the MEMS chip, which also provides gas-tight operating conditions for the cell.

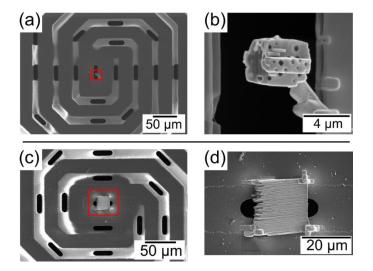


**Figure 2** Illustration of disassembled 2G (right) and 3G (left) cell with their internal gas-flow volumes (highlighted above). The fully assembled setups are shown below.

Beyond these aspects, there are some noticeable differences in design and function between the 2G and 3G cells. The use of one middle plate for 2G along with Si<sub>3</sub>N<sub>4</sub> membrane MEMS chips, but two middle plates for 3G with through-hole MEMS chips, directly influences the internal volume of the cells. The 2G cell has around 2.6 µl internal volume and the 3G around 24.5 µl. For 2G, the gas flows into the single middle plate, across the underside of the sample deposited on the back of MEMS-chip, and then out once again from the same plate (Figure S1). Meanwhile for 3G, the gas flows from the bottom middle plate, directly through the sample deposited on the through-hole MEMS chip, and finally to the outlet port of the top middle plate (Figure S1). Furthermore, the 2G cell has to be placed directly perpendicular to the incident X-ray beam, while the 3G cell allows tilting of  $\pm 35^{\circ}$  around the center of rotation with respect to the beam (or  $\pm 65^{\circ}$  for the naked MEMS chip). The intention is that all kind of samples can be used for 2G, including colloids, size-selected clusters or unsupported samples which require a membrane for stability. However, imaging studies are then limited to 2D XRP. On the other hand, the 3G cell with through-hole chips can exploit both 2D XRP and limitedangle PXCT, but this is restricted to pre-shaped samples which are then fixed to the chip through focused ion beam (FIB) manipulation or similar techniques. The general intention is to provide maximum flexibility to users of the hard X-ray nanoprobe endstation of beamline P06, who often have diverse sample requirements and structural features of interest.

#### 2.2. Sample preparation and mounting

Two sample types were used to demonstrate the use of the cells; (i) monolithic np-Au, (ii) hierarchical zeolite with intracrystalline macropores. Pure np-Au samples were prepared by dealloying of an Ag-Au alloy (i.e., 70 at% Ag and 30 at% Au) in nitric acid (65 wt%) as previously published (Lackmann et al., 2018). The sample was placed on a SEM sample holder stub (Figure S2), introduced to the FIB setup, then cut and shaped with a Ga<sup>+</sup> ion beam into a wedge (Figure S3, S4). The thicker part (1  $\mu$ m) was used for *in situ* XRP and thinner part (0.2 µm) for *ex situ* TEM. The wedge was extracted with the micromanipulator and placed across the window of a through-hole Wildfire chip (Figure S5), before being fixed by Pt glue at each corner. The as-prepared np-Au wedge sample is shown in Figure 3c-3d. Macroporous zeolites were synthesized by a templating method using silica and alumina precursors, followed by steam assisted crystallization to form macropores within the crystals, as described in previous publications (Machoke et al., 2015; Schwieger et al., 2016). The zeolite powder consisting of 2-4 µm crystals was introduced to the FIB setup, a suitable grain selected and placed across the window of a through-hole Wildfire chip, before being fixed with Pt-glue on one side. The as-prepared zeolite sample is shown in Figure 3a-3b. Sample preparation by FIB was performed at DESY NanoLab (Stierle et al., 2016). A detailed description of the different sample preparation steps is illustrated in the Supporting Information (Figure S2-S5). TEM, energy dispersive X-ray spectroscopy (EDX), and selected area electron diffraction (SAED) measurement were performed using a Wildfire sample holder (DENSsolutions, Delft, NL), on a Titan 80-300 (FEI) microscope operated at an acceleration voltage of 300 kV in STEM and TEM mode, at the Institute of Nanotechnology (INT) at Karlsruhe Institute of Technology.



**Figure 3** SEM images obtained during FIB preparation on Wildfire chips at DESY NanoLab: (a) micro/macroporous zeolite crystal and (b) zoom in of the highlighted area; (c) monolithic np-Au wedge and (d) zoom in of the highlighted area.

#### 2.3. In situ synchrotron X-ray imaging studies

All experiments were performed at the nanofocus endstation of beamline P06 at the PETRA III synchrotron radiation source (Hamburg, Germany) using the measurement parameters shown in Table 1. All XRP measurements were performed using an EIGER X 4M detector (DECTRIS Ltd, Switzerland) with 75\*75  $\mu$ m<sup>2</sup> pixel size and 2070\*2167 pixels. Measurement of nanoporous gold and macroporous zeolites were performed during two separate beamtimes.

Sample Type	np-Au	Zeolite
Energy (keV)	9.0	9.0
Optics	FZP <sup>a</sup>	FZP <sup>a</sup>
Sample to detector	2310	3470
distance (mm)		
Sample focus distance	in focus	0.6
(mm)		
Field of view ( $\mu m^2$ )	20*20; 5*5	4*4
Exposure time (ms)	10	500
Scantime per image	3-4	5-6
(min)		
Beam size (nm)	60	60 <sup>b</sup>
No. scanpoints	15625	144
Scan step size (nm)	40	333

 Table 1
 Experimental parameters during in situ XRP studies at P06 beamline of PETRA III.

<sup>a</sup>Fresnel zone plates, <sup>b</sup>at focal point

For *in situ* measurement of the np-Au sample, pure helium with a specific inlet flow of 1 ml/min adjusted by a mass flow controller was used to maintain a controlled atmosphere during *in situ* annealing treatment. The temperature was controlled via Joule heating and monitored using customized Labview software. Specific temperature conditions applied during imaging are indicated next to the relevant figures in the results section. The outlet flow from the cell was analyzed online using a Thermostar quadrupole mass spectrometer (Pfeiffer Vacuum GmbH, Aßlar, DE) to confirm the desired atmospheric composition was present during *in situ* experiments. In this case, He and residual O<sub>2</sub> (m/z = 4, 32) were monitored for the inert atmosphere. For measurement of the hierarchical zeolite by limited angle tomography, the sample on a Wildfire chip was placed within the 3G cell and aligned to the center of rotation with respect to the beam. 2D ptychographic projections

were recorded across an angular range of approximately  $\pm 35^{\circ}$  in 1.4° steps, leading to a total of 51 projections.

#### 2.4. Data processing

The algorithm used for ptychographic reconstruction was based on the (e)PIE algorithm (Maiden & Rodenburg, 2009). Cropping the diffraction patterns to 256×256 pixels led to a pixel size of 8.2 nm (for np-Au), and 8.5 nm (for zeolite) in the reconstructed images. To estimate the spatial resolution, a Fourier ring correlation (FRC) analysis (Van Heel & Schatz, 2005) was performed. As a common procedure, two individual scans of an identical sample area were reconstructed and compared. Before correlating the phase reconstruction, a Kaiser-Bessel window function with a size equal to 1 was applied to the images, in order to reduce artifacts caused by erroneous high frequencies resulting from the edges of the limited field of view of the reconstructions.

#### 3. Results

#### 3.1. Design process for the 2G and 3G in situ cells

The design of the 2G and 3G cells was directly inspired by the first generation *in situ* XRP cell developed by our group, denoted here as the 1G cell (Baier, Damsgaard, *et al.*, 2016). Development of the next generation cells was driven by several significant practical limitations of our own 1G cell and those previously described in the literature, which are summarized in the following section.

One of the first applications of in situ 2D XRP was to monitor CO<sub>2</sub> capture on Li<sub>2</sub>ZrO<sub>3</sub> materials, which was performed in a plexiglass sample enclosure. However, such an open sample environment is considerably different in volume to a closed reactor or cell. Both exclusion of ambient air and maintaining a defined gaseous environment such as CO<sub>2</sub> are therefore challenging tasks, particularly if hazardous gases are required (Høydalsvik et al., 2014). Later experiments used a scanning chip calorimeter to visualize thermal annealing processes in organic photovoltaic layers in combination with 2D XRP (Patil et al., 2016; Van den Brande et al., 2017). Although showing an excellent control over annealing temperatures with this setup, the same issue with controlling the gas environment is present and such a system is not optimal for heterogeneous catalysis studies with defined reaction conditions. A separate study used in situ XRP to observe the microstructure changes of geopolymers during thermal curing processes (Van Riessen et al., 2017), but unfortunately the setup and sample environment were not detailed, while it appears that the samples were heated in an open atmosphere. Recently an alternative cell design based on MEMS chips was reported and is similar to that used in this work (van Ravenhorst et al., 2018). The authors demonstrated the application of STXM with 50 nm spatial resolution, specifically by performing spectroscopic measurements around the Co K edge in absorption contrast mode. However, it is unknown whether this apparatus in its current form could

be used for XRP, which offers phase contrast imaging with far superior spatial resolution than STXM and can in any case be combined with nanofluorescence or nanodiffraction measurements, yielding more information. Furthermore, XRP offers the possibility to obtain complementary spectroscopic information through resonant XRP imaging (Hoppe *et al.*, 2013), or to identify and locate sample constituents by converting the observed phase shift to yield electron density maps of the sample (Diaz *et al.*, 2012). The geometry of the alternative MEMS chip design is also not suitable for 3D imaging either in electron microscopy or potentially with PXCT, although complementary TEM studies would be feasible.

Our previous work with the 1G cell was able to demonstrate complementary TEM and XRM, a contained gas environment and a wide range of applicable temperatures with indirect heating provided by a variable voltage power supply and an IR thermography camera. A point-by-point comparison of the 1G cell with the 2G and 3G cells presented in this work follows. The 2G and 3G cells described here have been improved with respect to many of the criteria mentioned above, particularly with respect to the 1G cell developed by our group. Firstly, they both exhibit significantly smaller internal gas flow volumes (volume ratio of  $1G:2G:3G = 500:2.6:24.5 \ \mu l = 192:1:9$ ). This is an important factor in determining the sample sizes necessary for operando studies, where the smaller the internal volumes, the more freedom available to use smaller sample sizes while being able to reliably detect dilute products. On the other hand, where relatively larger sample volumes are used, reactant conversion may be high enough to allow quantitative product analysis in addition to imaging. The sample size is therefore an important criterion both for the purpose of mass spectrometry characterization of the gas stream outlet, but is also relevant if complementary TEM studies are required. Preparation of relatively large or thick samples by FIB is both time intensive and may result in attenuation of the electron beam and poor resolution. The ability to effectively image either thick samples with X-ray imaging, or thin samples with electron and X-ray imaging adds a layer of flexibility to the possible uses of the setup (see np-Au wedge study below). In addition, the low internal cell volume actually leads to a smaller physical profile of the cell, which generally decreases the total weight of the setup. This is crucial to ensure accurate and error-free nano-precise positioning of the setup by the beamline sample stage motors. The 2G and 3G cells therefore come with a significant decrease in size and mass compared to the 1G cell and other cells reported earlier.

Another advantage of the current cells is the additional characterization capabilities on offer. Spectroscopic XRF analysis is possible in addition to XRP, which is extremely useful to map elemental distribution within the probed material. Although methods are available to accurately determine elemental speciation using XRP (e.g. resonant imaging around an elemental absorption edge (Hoppe *et al.*, 2013)), XRP does not always guarantee chemical contrast in the sample of interest. For ptychography beamlines optimised in the use of nanofocusing optics, such as P06 at PETRA III, the acquisition of highly spatially-resolved local fluorescence data is a natural advantage due to the small beam size. Provided the incident energy is above the absorption edge of interest, XRF mapping is complementary to XRP. Such measurements were not possible with the 1G cell due to the bulky cell body, which did not allow detector positioning at an appropriate angle to detect measurable fluorescence counts. At the moment XRF must be performed following slight rotation (25-35°) of the cells to face the detector, which can be positioned around  $110^{\circ}$  relative to the incident X-ray rather than the optimal angle of 90°. This also means that simultaneous XRF and XRP are not optimal, although they can be sequentially acquired on congruent sample fields of view with little delay between measurements. However, the necessary beam conditions for simultaneous XRF and XRP measurement modes are not always complementary in any case. Furthermore, the 3G cell has been designed for PXCT with limited angles, similar to the missing wedge principle commonly employed in electron tomography. This allows for large angle XRD up to a  $2\theta$  range of around  $70^{\circ}$ . The 1G cell was on the contrary strictly limited to 2D XRP.

The temperature control system is one of the most significant improvement over the original 1G setup. The 2G and 3G cells exhibit a direct and fast response to programmed temperature input due to the use of MEMS chips with 4-point resistivity measurement, allowing temperature readout and control in a feedback loop (see Supporting Information Figure S6). This capability has also been widely used in the *in situ* Wildfire series TEM sample holders (Gocyla *et al.*, 2018; Ren *et al.*, 2018). Furthermore, the specific resistivity of each chip under ambient conditions is calibrated during manufacture, improving the accuracy of all temperature-controlled experiments. With the 1G cell, no temperature feedback was used, necessitating a variable voltage power supply system and indirect temperature measurement with an IR camera, whose temperature readout and control is significantly less effective. This is partly due to the delay in recording the temperature from the camera and manually adjusting the power supply to obtain the desired condition. However, the indirect control mechanism also leaves the system vulnerable to unexpected changes in temperature, e.g. from changing gas conditions and therefore specific heat capacity of the local environment, or from thermal variation due to chemical reactions taking place on the chip.

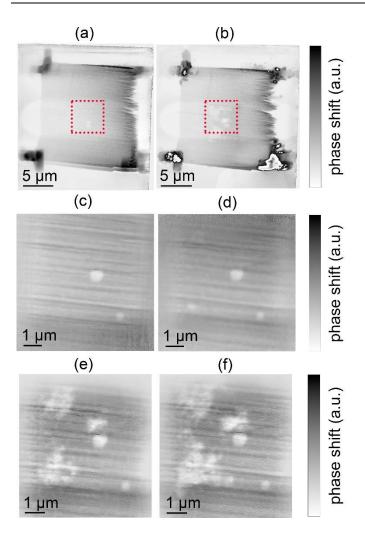
In summary, the cells offer significant current and potential improvements over similar setups previously described in literature:

- compatibility with a range of sample types, including colloids, metal nanoparticles, bulk materials and single catalyst grains;
- maintenance of a closed cell with easily controllable gas environment, allowing the application of oxidative, reductive or hazardous gases in a safe manner;
- small ratio of internal cell volume to sample volume, permitting high contact time between samples and reactant gases, and potentially facilitating the detection of gaseous products during X-ray imaging when large enough samples are present (*operando* imaging);

- low mass of the setup, mitigating vibrational instabilities and positioning errors when using nanoprecise sample stage motors, thereby leading to improved spatial resolution;
- capability to perform several complementary measurements (possibly simultaneously), including XRF, large angle XRD (nanospectroscopy / nanodiffraction);
- capability to perform complementary electron microscopy and ptychography on identical samples, including *in situ* electron microscopy with an appropriate sample holder;
- capability to perform 3D imaging by acquiring 2D projections at limited rotational angles;
- direct and accurate resistive heating, which may be easily programmed, monitored and precisely controlled via a feedback mechanism (±0.01 K in Figure S6) under specific desired gas atmospheres (e.g. inert He, O<sub>2</sub>, H<sub>2</sub>, reactive gases);

#### 3.2. Annealing of np-Au series in controlled gas environment using the 2G cell

The annealing of hierarchically-structured np-Au was chosen as a case study to demonstrate the capabilities of the fully commissioned in situ cells (Figure 1) and related infrastructure (Figure 2). Nanoporous gold is an ideal sample for XRP due to high phase contrast and large difference in electron density between the substrate and background air (Fam et al., 2018). Moreover, np-Au has a hierarchical structure of sponge-like 3D network, where its pores and ligaments form a macroscopic material spanning from nanometer to millimeter scales (Wichmann et al., 2013; Bagge-Hansen et al., 2014; Shi et al., 2014; Shi et al., 2016; Shi et al., 2017). This makes np-Au an excellent benchmark for evaluating the highest resolution achievable under in situ conditions (Larsson et al., 2019). Experiments were performed at elevated temperature up to 923 K while flowing He (1 ml/min) through the cell. A large  $20*20 \,\mu\text{m}^2$  overview scan of the np-Au wedge was recorded before and after heat treatment. For the high resolution *in situ* imaging series, a smaller  $5*5 \,\mu\text{m}^2$  field of view was selected from the center of the sample wedge. XRP reconstructions of the overview scan and selected in situ images are shown in Figure 4, with an estimated spatial resolution of 23 nm. The through-hole window of the MEMS chip can be observed as a lighter rounded rectangle shape in the middle of Figure 4a-b. Notably for hard X-ray imaging it is not strictly necessary to place the sample directly over such a window, although this will reduce background scattering. For potential TEM measurements on the other hand, the sample must be placed over such a window.



**Figure 4** Ptychography images from thermal annealing of np-Au under He environment. Overview scans: (a) before and (b) after thermal annealing. Highlighted area in (a-b) shown: (c) at 293 K, (d) 923 K, (e) 923 K after 15 min, (f) 923 K after 30 min. Dark spots in phase maps indicates areas rich in Au, while brighter voids indicate annealing and absence of Au ligaments.

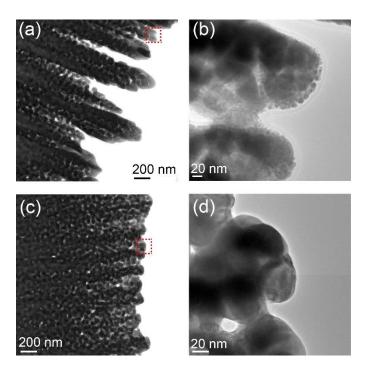
The sample was thermally stable under inert gas atmosphere up to 923 K, after which the coarsening process was strongly visible. The temperature was kept constant at 923 K and sequential 2D XRP images were acquired to illustrate the progression of the coarsening process. The high accuracy of the temperature control system can be seen in the experimental readout plot in the supporting information (Figure S6). Coarsening was observed as large-scale annealing of fine gold ligaments (which were previously at or below the resolution limit), to form larger ligaments and leaving behind irregular shaped voids of lower electron density, therefore lower local concentration of Au. Individual ligaments are faintly visible around the voids in Figure 4e-f. In comparison with previous experiments on np-Au, the coarsening process was studied by both *in situ* TEM and *in situ* ptychography, with the onset of coarsening found to be at 523-573 K in 100 kPa of synthetic air (20% O<sub>2</sub>/N<sub>2</sub>), 573 K in 320 Pa of pure O<sub>2</sub>, and 973 K in vacuum. (Baier, Damsgaard, *et al.*, 2016; Baier, Wittstock, *et al.*, 2016).

research papers

It was previously concluded that both the atmosphere composition and the pressure affect material stability. An oxygen containing atmosphere at any pressure may reasonably be expected to interact more strongly with the Au surface that inert He, therefore the onset of coarsening observed here at 923 K lies somewhere between the values observed in synthetic air or pure oxygen, and vacuum conditions. This additionally proves the maintenance of an inert environment inside the cell. A notable improvement over previous measurements is that these were carried out at 100 K intervals (TEM studies) and 25-30 K intervals (*in situ* XRP), whereas here it was possible to use consecutive temperature steps of 10 K, leading to greater precision in determining the coarsening onset temperature. Comparing the first and last overview image in Figure 4a-b, it should be noted that the Pt glue fixed on the corner of the sample for stability via FIB partly disintegrated. For future studies the deposition of more temperature stable materials, e.g. tungsten, may be an advantage. Another important point to consider in this case is the unavoidable thermal drift caused by expansion of the MEMS chip viewing area, which prompts users either to find a 'natural' marker for determining the extent of drift from the area of interest, or to make a synthetic marker, e.g. deposition of Pt ring, via FIB prior to XRP measurements. In this experiment, the edge of the MEMS chip window was used as a natural marker. Also notable is how the coarsening process appeared to be more intense precisely in the area scanned continually during the temperature series. This aggravated coarsening behavior is suggested to be influenced by beam effects, since the area outside the field of view was less affected.

To demonstrate the possibility for complementary measurements on a single sample, TEM was conducted on the thin part of the np-Au wedge before and after in situ XRP as shown in Figure 5. The structural difference is noticeable particularly between Figure 5b-d, where the np-Au ligaments appear more consolidated as expected following thermal annealing at 923 K (Baier, Damsgaard, et al., 2016; Baier, Wittstock, et al., 2016). In addition, some minor contamination was observed at the border of the ligaments (Figure 5b), which was characterised as containing Si and Pt using EDX analysis (see Supporting Information Figure S11, EDX quantification in Table S1). Such contamination could originate from the  $Si_3N_4$  layer present on the MEMS chips or the Si chip body, which may have been deposited during the process of attaching the sample wedge to the Wildfire chip by FIB. This would also explain the source of Pt contamination, during gluing of the wedge to the MEMS chip. The Si layer was still detected even after thermal treatment (Figure 5d) although it became significantly thinner probably due to the influence of high temperature. While such contamination is unfortunate, it is also a common feature of FIB preparation and is difficult to exclude, however it is not expected that the complete sample wedge was affected particularly for XRP measurements, where the sample thickness in the region of interest was estimated as 600 nm. The composition of the np-Au sample was also confirmed as metallic gold by examining the Au lattice spacing by high resolution TEM (d = $0.236 \text{ nm}, [1\ 1\ 1]$  plane of Au crystal (PDF 99-0056)) and by SAED (d = 0.234 nm) (see Supporting Information Figure S12-S13). These measurements prove the capability of the setup to allow detailed

characterisation of identical samples by X-ray and electron microscopy, giving access to multiple sample length scales and spatial resolutions down to sub-nanometer level.

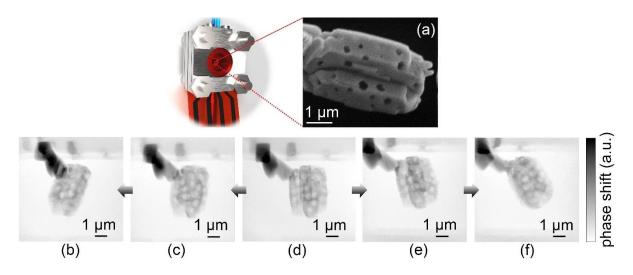


**Figure 5** TEM images of np-Au: (a) before *in situ* thermal annealing and (b) zoom in on the highlighted area; (c) after *in situ* thermal annealing at 923 K and (d) zoom in on the highlighted area.

# 3.3. Limited rotational angle 3D ptychography of hierarchical macroporous zeolite using the 3G cell

The 3G cell used in this case study matches all the experimental capabilities of the 2G cell described previously. However, the 3G cell was designed to furthermore permit *in situ* imaging under a range of tilting angles, therefore unlocking *in situ* PXCT in a closed cell as a viable characterization technique for the first time. To demonstrate the potential of the 3G cell to perform PXCT, tilting angles were tested using a single crystal of hierarchically porous zeolite. Consisting of 2-4  $\mu$ m crystals enclosing micropores (< 2nm) along with interior voids of several hundred nm, the macroporous zeolite therefore functions as a good test sample for 3D imaging, with strongly identifiable interior features (Machoke *et al.*, 2015; Schwieger *et al.*, 2016; Przybilla *et al.*, 2018). It should be noted that the zeolite micropores present (<2 nm) are challenging to observe except potentially with high resolution electron microscopy, which was not performed on the specific sample used here. Tomographic PXCT measurements were performed at ambient temperature and He gas environment with the sample placed in the fully assembled 3G cell. Figure 6d shows the ptychographic image taken at 0° tilting angle, i.e. with the cell in its normal position perpendicular to the incident beam. The macroporous

structure of the zeolite can clearly be observed as a series of spherical voids within the catalyst grain. The permitted angular range was eventually found to be approximately  $\pm 35^{\circ}$ , as indicated by the image series shown in Figure 6. Beyond these, the X-ray beam was blocked by the cell body. Notably, by removing the chip from the cell body, rotational angles of  $\pm 65^{\circ}$  could be reached. While images were acquired at ambient temperature, this was not due to limited functionality of the cell but rather due to high thermal stability of the zeolite material and the lack of any obvious thermal annealing process like for np-Au. The zeolite sample served primarily as a test object, but was measured within the assembled 3G cell, which is known to have identical control over temperature and gas conditions as the 2G cell presented earlier. The zeolite serves therefore as a good proof-of-concept study for combining PXCT and *in situ* measurements on other systems in the future, such as *in situ* drying, annealing or chemical reactions.



**Figure 6** Tilting angle tests using micro/macroporous zeolite as a case study: (a) illustration of the 3G cell with corresponding SEM image of the zeolite crystal on a MEMS chip, and ptychography images of the specimen at tilting angles with respect to the incident beam: (b)  $35^{\circ}$ , (c)  $15^{\circ}$ , (d)  $0^{\circ}$ , (e) -  $15^{\circ}$ , (f) - $35^{\circ}$ . Dark spots in phase maps indicates areas rich in Si/Al. Pt-glue is visible as the dark region in the upper left of each image.

Although the 2D projection series was not tomographically reconstructed in the present work, since appropriate algorithms have not yet been implemented for handling such data, there are several opportunities to improve the data acquisition range and therefore eventual quality of the reconstructed data. Firstly, in the case that a contained sample environment is not necessary throughout an entire experiment, the sample can readily be treated under certain conditions of temperature or gas, then simply removed from the cell at regular intervals to perform tomography scans. This procedure could be repeated to obtain an image series during thermal treatment covering  $\pm 65^{\circ}$ , which is analogous to

that used in electron tomography for data reconstruction with a missing wedge in the 180° rotational range. Secondly, if maintaining an *in situ* environment is essential to the experiment (e.g. due to sample instability in air or water), the  $\pm 35^{\circ}$  series acquired during temperature or gas treatment could be supplemented with a more detailed  $\pm 65^{\circ}$  scan both before and after the experiment. One proposal to reconstruct such data is through a machine learning assisted method, whereby the larger missing wedge obtained during  $\pm 35^{\circ}$  measurement could be partly mitigated by utilizing the smaller missing wedge data of the  $\pm 65^{\circ}$  measurement. Such data treatment possibilities are rather novel for PXCT and are currently being explored. In summary, the ability to record even limited 3D data series under fully *in situ* conditions is a significant milestone for synchrotron nanotomography, and is shown here for the first time to be feasible using the 3G cell apparatus.

#### 4. Discussion

While the 2G and 3G cells described here have essentially finished commissioning and are ready to be employed for general users of beamline P06 and PETRA III, several improvements and future advances are nevertheless anticipated. Potential improvements to the cell design could focus on reducing the physical profile and mass even further, therefore leading to improved sample stability and minimizing the harmful effects of mechanical vibrations on spatial resolution. In any case sample stability has been shown to be marginally less crucial for ptychography than for analogous measurements using STXM for example, since ptychography can readily operate with a less focused beam or the sample out of the focal position, while still obtaining superior spatial resolution in the reconstructed data (Pfeiffer, 2017; Schroer et al., 2017). For the 3G cell specifically, increasing the possible rotational angles by thinning the cell body design to increase the solid angle, or using alternative MEMS chips designed specifically for electron tomography may be readily achievable in the near future. To improve the range of experimental conditions, alternative window materials to thin Kapton could be explored to allow potential studies at elevated pressures greater than 100 kPa. Finally, there is significant room for development of 3D PXCT under *in situ* conditions, particularly concerning data analysis. It should be noted that reconstruction of 3D tomographic data with limited rotational angles may be challenging and prone to artefacts and errors depending on the reconstruction algorithm, although missing wedge measurements are typically acquired as standard using electron tomography. Data reconstruction could also be assisted by complementary TEM tomography, provided the sample dimensions allow for both TEM tomography and PXCT on the same region of interest. As the 2G and 3G cells are developed as an enabling technology for general users of beamline P06 and PETRA III, considering the range of potential users and sample types investigated at nanoprobe beamlines, it is feasible to assume that not all possible functionality of the cell may necessarily be needed simultaneously. In any case, the potential of the 3G cell for performing PXCT

under *in situ* conditions, even with currently limited angular range, is a remarkable advance on currently available sample environments, and may find widespread use beyond the field of catalysis. Finally, it is also important to note the imminent arrival or planning of 4<sup>th</sup> generation and/or diffraction limited storage rings, such as ESRF-EBS, PETRA IV or SLS 2.0 (Schroer *et al.*, 2018). The improved beam properties are predicted to strongly benefit ptychography, particularly through the increased coherent flux available. The time is therefore right to develop and commission dedicated sample environments to take full advantage of improvements in imaging speed, spatial resolution and coherent flux, and to fully exploit these new capabilities for the catalysis and materials science community.

#### 5. Conclusions

Two new modular 'nanoreactors' for complementary imaging at synchrotron and in electron microscopes have been designed and commissioned at the hard X-ray nanoprobe endstation at beamline P06 of the PETRA III synchrotron radiation source. The cells offer numerous advantages over previously available sample environments. In situ XRP studies of thermal annealing processes under gas flow on monolithic np-Au were successfully conducted using an accurate and easily controlled heating and gas flow setup. For the implementation of thermal annealing processes, the sample deposition, accurate control and ease of use of the temperature controller setup are of high importance. Complementary TEM measurements on the same MEMS chip were also demonstrated, showing the ability to asses multiple hierarchical length scales of the same sample. Hierarchical zeolite samples were used to demonstrate the tilting capability of the cells for potential ptychographic tomographic studies on catalysts and functional materials either: (i) under in situ conditions, or (ii) through sequential treatment under reaction conditions, followed by imaging outside of the cell. However, the limitations of collecting and reconstructing tomography data with less than 180° angular range should be carefully considered. Other potential studies may include: (i) elemental analysis through fluorescence measurements at the synchrotron or using complementary TEM-EDX, (ii) crystallinity analysis through large angle XRD at the synchrotron and/or SAED for electron microscopy, (iii) oxidation state analysis through tuning incident X-ray energy around an absorption edge at the synchrotron (resonant ptychographic imaging), or by electron energy loss spectroscopy (EELS) for electron microscopy. A variety of applications ranging from gas sensing, gas storage, redox reactions, and thermal treatments, can benefit from use of these cells, which will presently be made available for general users of beamline P06 and PETRA III.

**Acknowledgements** This work was supported by the Bundesministerium für Bildung und Forschung (BMBF) project "MicTomoCat" (05K16VK1), and the EU-H2020 research and innovation program under grant agreement No 654360 of Nanoscience Foundries and Fine Analysis (NFFA). We acknowledge DESY (Hamburg, Germany), a member of the Helmholtz Association HGF, for the provision of experimental facilities. Parts of this research were carried out at beamline P06 at PETRA III through a Long-Term Proposal (LTP 20170010). We further acknowledge DESY for access to FIB at DESY NanoLab granted by BMBF under grant no. 5K13WC3 (PT-DESY), and the Karlsruhe Nano Micro Facility (KNMF) of Karlsruhe Institute of Technology for access to electron microscopy. We thank Dr. Peter Marek, Dr. Torsten Scherer, and Heino Besser (Karlsruhe Institute of Technology) for helpful discussions regarding sample preparation; Wu Wang (Karlsruhe Institute of Technology) for assistance with TEM measurements; Christina Ossig, Saba Alizadehfanaloo, Dr. Jan Garrevoet, Dr. Johannes Hagemann, and Dr. Mikhail Lyubomirskiy (DESY) for their assistance during beamtime; Tobias Weissenberger and Prof. Wilhelm Schwieger (Friedrich-Alexander University Erlangen-Nuremberg) for preparation and provision of the zeolite sample; and finally Asst. Prof. Christian Damsgaard and Dr. Sina Baier (Technical University of Denmark) for discussions and preliminary work on designing the sample environment.

#### References

- Bagge-Hansen, M., Wichmann, A., Wittstock, A., Lee, J. R. I., Ye, J., Willey, T. M., Kuntz, J. D., Van Buuren, T., Biener, J., Bäumer, M. & Biener, M. M. (2014). J. Phys. Chem. C 118, 4078-4084.
- Baier, S., Damsgaard, C. D., Klumpp, M., Reinhardt, J., Sheppard, T., Balogh, Z., Kasama, T., Benzi, F., Wagner, J. B., Schwieger, W., Schroer, C. G. & Grunwaldt, J.-D. (2017). *Microsc. Microanal.* 23, 501-512.
- Baier, S., Damsgaard, C. D., Scholz, M., Benzi, F., Rochet, A., Hoppe, R., Scherer, T., Shi, J., Wittstock, A., Weinhausen, B., Wagner, J. B., Schroer, C. G. & Grunwaldt, J. D. (2016). *Microsc. Microanal.* 22, 178-188.
- Baier, S., Wittstock, A., Damsgaard, C. D., Diaz, A., Reinhardt, J., Benzi, F., Shi, J. J., Scherer, T., Wang, D., Kubel, C., Schroer, C. G. & Grunwaldt, J. D. (2016). *RSC Adv.* 6, 83031-83043.
- Bañares, M. A. (2005). Catal. Today 100, 71-77.
- Beale, A. M., Jacques, S. D. M. & Weckhuysen, B. M. (2010). Chem. Soc. Rev. 39, 4656-4672.
- Buurmans, I. L. C. & Weckhuysen, B. M. (2012). Nat. Chem. 4, 873-886.
- De Smit, E., Swart, I., Creemer, J. F., Hoveling, G. H., Gilles, M. K., Tyliszczak, T., Kooyman, P. J., Zandbergen, H. W., Morin, C., Weckhuysen, B. M. & De Groot, F. M. F. (2008). *Nature* **456**, 222-225.
- Diaz, A., Trtik, P., Guizar-Sicairos, M., Menzel, A., Thibault, P. & Bunk, O. (2012). *Phys. Rev. B* 85, 020104.
- Fam, Y., Sheppard, T. L., Diaz, A., Scherer, T., Holler, M., Wang, W., Wang, D., Brenner, P., Wittstock, A. & Grunwaldt, J.-D. (2018). *ChemCatChem* 10, 2858-2867.
- Frenkel, A. I. & Van Bokhoven, J. A. (2014). J. Synchrotron Rad. 21, 1084-1089.
- Gocyla, M., Kuehl, S., Shviro, M., Heyen, H., Selve, S., Dunin-Borkowski, R. E., Heggen, M. & Strasser, P. (2018). ACS Nano.
- Grunwaldt, J. D. & Clausen, B. S. (2002). Top. Catal. 18, 37-43.
- Grunwaldt, J. D. & Schroer, C. G. (2010). Chem. Soc. Rev. 39, 4741-4753.
- Grunwaldt, J. D., Wagner, J. B. & Dunin-Borkowski, R. E. (2013). ChemCatChem 5, 62-80.

- Guizar-Sicairos, M., Holler, M., Diaz, A., da Silva, J. C., Tsai, E. H. R., Bunk, O., Martinez-Perez, C., Donoghue, P. C. J., Wellman, C. H. & Menzel, A. (2015). *Proc. SPIE*, **9592**, 9592A.
- Hoppe, R., Reinhardt, J., Hofmann, G., Patommel, J., Grunwaldt, J. D., Damsgaard, C. D., Wellenreuther, G., Falkenberg, G. & Schroer, C. G. (2013). *Appl. Phys. Lett.* **102**, 203104.
- Høydalsvik, K., Bø Fløystad, J., Zhao, T., Esmaeili, M., Diaz, A., Andreasen, J. W., Mathiesen, R. H., Rønning, M. & Breiby, D. W. (2014). *Appl. Phys. Lett.* **104**, 241909.
- Lackmann, A., Bäumer, M., Wittstock, G. & Wittstock, A. (2018). Nanoscale 10, 17166-17173.
- Larsson, E., Gursoy, D., De Carlo, F., Lilleodden, E., Storm, M., Wilde, F., Hu, K., Muller, M. & Greving, I. (2019). J. Synchrotron Rad. 26, 194-204.
- Machoke, A. G., Beltrán, A. M., Inayat, A., Winter, B., Weissenberger, T., Kruse, N., Güttel, R., Spiecker, E. & Schwieger, W. (2015). *Adv. Mater.* 27, 1066-1070.
- Maiden, A. M. & Rodenburg, J. M. (2009). Ultramicroscopy 109, 1256-1262.
- Patil, N., Skjønsfjell, E. T. B., Van den Brande, N., Chavez Panduro, E. A., Claessens, R., Guizar-Sicairos, M., Van Mele, B. & Breiby, D. W. (2016). *PLoS One* **11**, e0158345.
- Pfeiffer, F. (2017). Nat. Photonics 12, 9-17.
- Piazza, V., Weinhausen, B., Diaz, A., Dammann, C., Maurer, C., Reynolds, M., Burghammer, M. & Köster, S. (2014). ACS Nano 8, 12228-12237.
- Przybilla, T., Zubiri, B. A., Beltrán, A. M., Butz, B., Machoke, A. G. F., Inayat, A., Distaso, M., Peukert, W., Schwieger, W. & Spiecker, E. (2018). *Small Methods* 2, 1700276.
- Ren, G. Q., Tang, Y., Liu, K. P., Su, Y., Miao, S., Liu, W., Cong, W. M., Wang, X. D., Li, W. Z., Li, J. & Zhang, T. (2018). *Nano. Lett.* 18, 6489-6493.
- Sala, S., Kuppili, V. S. C., Chalkidis, S., Batey, D. J., Shi, X., Rau, C. & Thibault, P. (2018). *J. Synchrotron Rad.* **25**, 1214-1221.
- Schroer, C. G., Agapov, I., Brefeld, W., Brinkmann, R., Chae, Y. C., Chao, H. C., Eriksson, M., Keil, J., Nuel Gavalda, X., Rohlsberger, R., Seeck, O. H., Sprung, M., Tischer, M., Wanzenberg, R. & Weckert, E. (2018). J. Synchrotron Rad. 25, 1277-1290.
- Schroer, C. G., Seyrich, M., Kahnt, M., Botta, S., Döhrmann, R., Falkenberg, G., Garrevoet, J., Lyubomirskiy, M., Scholz, M., Schropp, A. & Wittwer, F. (2017). *Proc. SPIE* 10389, 103890E.
- Schropp, A., Hoppe, R., Patommel, J., Samberg, D., Seiboth, F., Stephan, S., Wellenreuther, G., Falkenberg, G. & Schroer, C. G. (2012). *Appl. Phys. Lett.* **100**, 253112.
- Schwieger, W., Machoke, A. G., Weissenberger, T., Inayat, A., Selvam, T., Klumpp, M. & Inayat, A. (2016). *Chem. Soc. Rev.* **45**, 3353-3376.
- Seiboth, F., Schropp, A., Scholz, M., Wittwer, F., Rödel, C., Wünsche, M., Ullsperger, T., Nolte, S., Rahomäki, J., Parfeniukas, K., Giakoumidis, S., Vogt, U., Wagner, U., Rau, C., Boesenberg, U., Garrevoet, J., Falkenberg, G., Galtier, E. C., Ja Lee, H., Nagler, B. & Schroer, C. G. (2017). *Nat. Commun.* 8, 14623.
- Shapiro, D. A., Yu, Y. S., Tyliszczak, T., Cabana, J., Celestre, R., Chao, W., Kaznatcheev, K., Kilcoyne, A. L. D., Maia, F., Marchesini, S., Meng, Y. S., Warwick, T., Yang, L. L. & Padmore, H. A. (2014). *Nat. Photonics* 8, 765-769.
- Shi, J., Mahr, C., Murshed, M. M., Gesing, T. M., Rosenauer, A., Bäumer, M. & Wittstock, A. (2017). *Phys. Chem. Chem. Phys.* **19**, 8880-8888.
- Shi, J., Mahr, C., Murshed, M. M., Zielasek, V., Rosenauer, A., Gesing, T. M., Bäumer, M. & Wittstock, A. (2016). *Catal. Sci. Technol.* 6, 5311-5319.
- Shi, J., Schaefer, A., Wichmann, A., Murshed, M. M., Gesing, T. M., Wittstock, A. & Bäumer, M. (2014). J. Phys. Chem. C 118, 29270-29277.
- Stierle, A., Keller, T. F., Noei, H., Vonk, V. & Roehlsberger, R. (2016). Journal of Large-Scale Research Facilities 2, 1-9.
- Thibault, P., Dierolf, M., Menzel, A., Bunk, O., David, C. & Pfeiffer, F. (2008). *Science* **321**, 379-382.
- Thomas, J. M. & Hernandez-Garrido, J. C. (2009). Angew. Chem. Int. Ed. 48, 3904-3907.
- Topsøe, H. (2003). J. Catal. 216, 155-164.
- Van den Brande, N., Patil, N., Guizar-Sicairos, M., Claessens, R., Van Assche, G., Breiby, D. W. & Van Mele, B. (2017). *Org. Electron.* **41**, 319-326.
- Van Heel, M. & Schatz, M. (2005). J. Struct. Biol. 151, 250-262.

- van Ravenhorst, I. K., Vogt, C., Oosterbeek, H., Bossers, K. W., Moya-Cancino, J. G., van Bavel, A. P., van der Eerden, A. M. J., Vine, D., de Groot, F. M. F., Meirer, F. & Weckhuysen, B. M. (2018). Angew. Chem. Int. Ed. 57, 11957-11962.
- Van Riessen, A., Rickard, W. D. A., Williams, R. P. & Van Riessen, G. A. (2017). J. Ceram. Sci. Technol. 8, 421-431.
- Vila-Comamala, J., Diaz, A., Guizar-Sicairos, M., Mantion, A., Kewish, C. M., Menzel, A., Bunk, O. & David, C. (2011). *Opt. Express* **19**, 21333-21344.
- Weckhuysen, B. M. (2002). Chem. Commun. 2, 97-110.
- Weckhuysen, B. M. (2009). Angew. Chem. Int. Ed. 48, 4910-4943.
- Weker, J. N., Huang, X. & Toney, M. F. (2016). Curr. Opin. Chem. Eng. 12, 14-21.
- Wichmann, A., Wittstock, A., Frank, K., Biener, M. M., Neumann, B., M\u00e4dler, L., Biener, J., Rosenauer, A. & B\u00e4umer, M. (2013). *ChemCatChem* 5, 2037-2043.
- Wise, A. M., Weker, J. N., Kalirai, S., Farmand, M., Shapiro, D. A., Meirer, F. & Weckhuysen, B. M. (2016). ACS Catal. 6, 2178-2181.
- Zhu, C., Harder, R., Diaz, A., Komanicky, V., Barbour, A., Xu, R., Huang, X., Liu, Y., Pierce, M. S., Menzel, A. & You, H. (2015). *Appl. Phys. Lett.* **106**, 101604.

### **Supporting information**

#### S1. Gas flow simulation of 2G/3G cells

In ANSYS AIM (Student Version, ANSYS, Inc.), Fluid Flow template module was used to simulate the gas flow in the 2G and 3G cell. Specific parameters were kept as default unless specifically mentioned. The geometry was generated by the integrated Space Claim Direct Modeler (SDCM) and "Define mesh manually" was chosen. In Fluid-specific options, "Swirling flow" was ticked to enable any significant rotating or twisting movement of the gas. The simulation focus was set as "Steady-state fluid flow". Number of fluid regions was selected to be "1", i.e. Air as the Material Sample, and "Compressible flow (ideal gas)" was ticked as an additional flow physics. For the meshing process settings, the resolution was set to 4, "Fluid flow or fluid-solid heat transfer" was selected for Engineering intent, and the refinement mechanism of "Curvature and proximity" was used. In Mesh controls, the element shape was set to "Automatic", where it meshed sweepable bodies with hexahedrons and provided a tetrahedral mesh on bodies that were not sweepable. The number of generated nodes was 46556 for 2G cell and 95272 for 3G cell, respectively.

For the Physics parameters, the whole SDCM-generated volume (Figure 3) was specified as the location of Physics Regions. "Laminar" flow model was selected as the Flow Model since a Reynolds number (Re) of 9 was estimated according to:  $Re = \frac{\rho * \nu * D_H}{\mu}$ , where  $\rho$  is the mass density of air (1.1839) kg m<sup>-3</sup> at T = 298 K),  $\upsilon$  is the mean velocity of air (0.236 m s<sup>-1</sup> in this case from a volumetric flow of 1 ml min<sup>-1</sup>),  $D_{\rm H}$  is the hydraulic diameter of the inlet/outlet channel (0.3 mm), and  $\mu$  is the dynamic viscosity of air (18.6 µPa s). The Inlet/Outlet Boundary was located on either one cross-section face of the long cylindrical channels with "Mixed" subsonic-supersonic regime and Gauge static pressure of 0 Pa. Additional parameter settings were for the inlet with gas Velocity magnitude of 0.236 m s<sup>-1</sup> and Temperature of 298 K. The rest of the faces on the SDCM-generated volume was determined as the Wall Boundary. The Solver Options was left as default, where the solution would converge with Residual Tolerance of 1E-05 and Maximum iteration number of 1000; Solution advancement exponent was kept 0 under Calculation Control; and "Least squares cell-based" Gradient method was used for Discretization Control with "Second-order upwind" Advection and "Automatic" Pressure scheme. As the results, the convergence criteria were met after 45 iterations with residual tolerances up to 9.69E-06 for 2G cell, and 773 iterations with residual tolerances up to 2.15E-07 for 3G cell. The fluid flow profiles of the 2G and 3G cell are displayed in Figure S1.

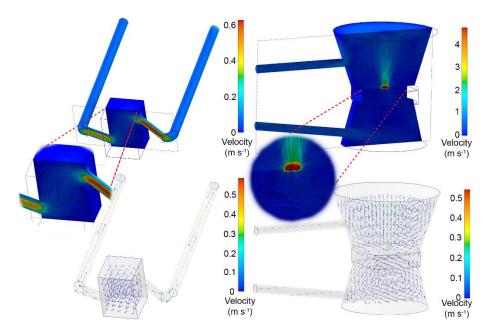


Figure S1 Internal gas-flow volume and simulation of 2G cell (left) and 3G cell (right).

#### S2. Sample preparation of np-Au series via FIB

The description below (Figure S2-S5) only applies to the preparation of np-Au samples. Each original sample was a solid pellet, a piece of which was deposited on a SEM stub and then on a lift-out grid, which acted as an intermediate stage to the final sample holder, i.e. MEMS chip (Figure S2). All sample preparation steps were performed in a dual-beam focused ion beam. For details in each stage after mounting the stub, the piece was cut again and shaped into a smaller block / trapezoidal prism (Figure S3). The block was then transferred onto the lift-out grid, where a much smaller wedge shape was eventually obtained (Figure S4). Last, the final transfer onto the MEMS-chip was made on the spiral center area of the chip and glued with Pt on the corner to stabilize the position (Figure S5).

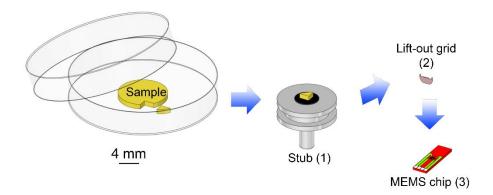


Figure S2 Overview of np-Au sample preparation on the MEMS chip via FIB.

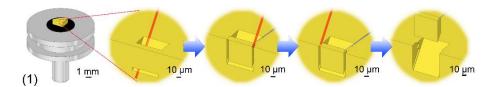


Figure S3 Initial np-Au extraction on a SEM stub to make a block for preparing several samples.

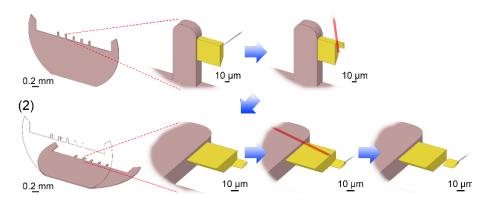


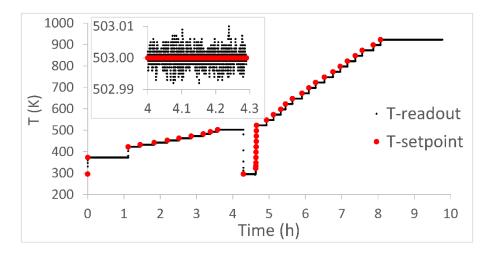
Figure S4 Final cut after transfer to intermediate lift-out grid and thinning of block into a wedge.



Figure S5 Transfer and deposition of the wedge on the MEMS chip.

#### S3. Temperature stability of the heating interface system

Since the MEMS chips and parts of heating interface system are commercially available and tested, the temperature readout and control process proved to be robust as shown in Figure S6. Excellent stability can be observed in the step functions between heating points, where fluctuations of <1 K were observed during temperature adjustment.



**Figure S6** Plot of temperature readout vs time via the integrated temperature control system, recorded during thermal annealing study of nanoporous gold. The valley between the fourth and fifth hour of the measurement resulted from pausing the experiment due to loss of beam.

#### S4. Determination of the spatial resolution

To estimate the spatial resolution of the ptychograms obtained, a Fourier Ring Correlation (FRC) analysis was performed (Van Heel & Schatz, 2005), depicted in Figure S7 for colloidal Au, and in Figure S8 for nanoporous gold. The intersection of the FRC datapoint with the ½ -bit threshold curve provides an estimation of the spatial resolution in nm.

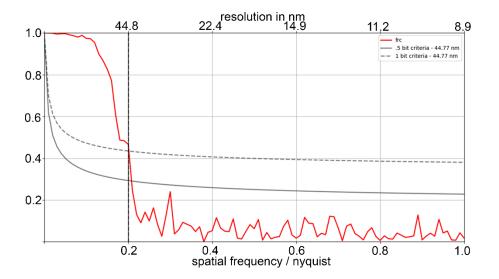


Figure S7 FRC of the ptychogram of colloidal Au sample.

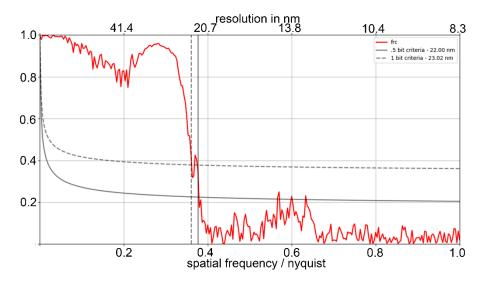


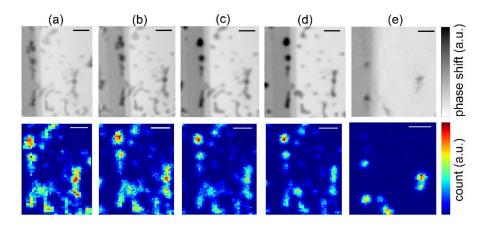
Figure S8 FRC of the ptychogram of np-Au sample.

#### S5. In situ sintering of Au colloids - early cell prototypes using 2G cell

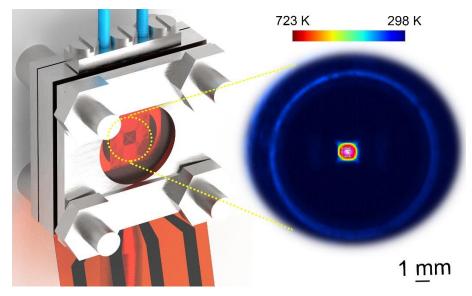
A solution of colloidal Au nanoparticles stabilized in citrate (Sigma-Aldrich Chemie GmbH, Taufkirchen, DE) with ~50 nm uniform particle size were applied directly to the sample area of the MEMS chips and the solvent left to evaporate for one hour under flowing air. The experiment using colloidal Au nanoparticle sample was performed at the nanofocus endstation of beamline P06 at the PETRA III synchrotron radiation source (Hamburg, Germany) (Schroer et al., 2017), using the energy of 15 keV, nano-focusing refractive X-ray lenses as the optics, and EIGER X 4M detector. The sample was positioned in the beam focus and located at 4.16 m from the detector. Moreover, the sample was scanned under 2-6 min per image with a field of view of  $2.5*2.5 \ \mu\text{m}^2$ , exposure time of 50 ms, 500 scanpoints, and scanning step size of 100 nm. The algorithm used for ptychographic reconstruction was based on the (e)PIE algorithm. Cropping the diffraction patterns to  $256\times256$  pixels led to a pixel size of 8.9 nm in the reconstructed images. To estimate the spatial resolution, a Fourier ring correlation (FRC) analysis was performed.

During measurement of the Au colloid sample, XRF signal was collected with a single channel Vortex silicon drift detector at 50 nm intervals with a collection time of 50 ms/pixel. The detector was placed on a moveable table and was located at an angle approximately 72 ° to the incident beam. It should be noted that the cell body blocks positioning of the detector ideally perpendicular to the incident beam. An XRF scan in high flux mode was recorded by scanning the sample over a field of view of 5x5 and  $15 \times 15 \ \mu\text{m}^2$  with a step size of 50 nm. At each scanning position an XRF spectrum was collected for an exposure time of 2 s. The XRF spectra were fitted by AXIL software for the analysis of line intensities of the elements.

Colloidal Au particles with a size of 50 nm were utilized to confirm the applicability and feasibility of the 2G cell for *in situ* XRP and XRF. For this study, an early prototype of the 2G cell was used. This prototype consisted of the same physical cell profile shown in Figure 2 including electrical contacts, but without the gas tight O-ring and window assembly. Experiments were therefore performed only at elevated temperature up to 773 K but with ambient gas conditions. The ptychography images (Figure S9 - top row) imply that the spatial resolution should be at least 50 nm as colloidal Au can be clearly resolved, where high local concentration of colloidal Au is indicated by the darker intensity. Using FRC, the spatial resolution was in fact estimated to be 45 nm as shown in Figure S7. However, the Au fluorescence maps (Figure S9 – bottom row) are more suitable for locating colloidal Au, with increased local concentration leading to higher fluorescence counts. The Au colloids showed a distribution of larger connected ligaments, likely from clustered bunches of colloids, together with a homogeneous distribution of smaller particles, particularly visible in the upper middle of Figure S9ab. During temperature treatment, the colloidal Au underwent several modifications including aggregation and/or recombination of individual particles into larger clusters. This was evidenced by the contraction of ligament shapes into spherical bodies which began already at 423 K, together with the apparent disappearance of smaller particles in close vicinity to the more densely concentrated ones. These observations are typically expected for unsupported particles at elevated temperatures, at which the organic surfactant likely decomposes leading to aggregation. The complete disappearance of many smaller Au particles was also observed particularly at 773 K, which was somewhat unexpected since particle migration may not be expected to proceed across several microns. However, this could be due to the unstable deposition of unsupported particles directly on the  $Si_3N_4$  window of the MEMS-chip, so the thermal effect may have caused them to significantly drift or fall away from the chip. As noted above, instead of the Digiheater temperature control unit, a variable voltage power supply and an IR thermographic camera were used as in previous work(Baier, Damsgaard, et al., 2016). A typical IR thermography image captured from the cell during operation is shown in Figure S10. In this case, wires connected to the power supply were soldered directly to the power in/out contact of the printed circuit. As such, accurate control of the sample temperature was not guaranteed during the experiment. As noted previously, a sudden variation in local gas composition or local chemical reactions on the chip may cause significant temperature spikes, as observed in previous work(Baier, Damsgaard, et al., 2016). This might also contribute to the sudden disappearance of colloidal Au at 773 K. This early case study highlights the necessity of a stable and dependable temperature control system, which was later integrated into both the 2G and 3G setups detailed in Figure 1 and Figure 2.



**Figure S9** Ptychography images (top) and Au fluorescence maps (bottom) during thermal annealing of colloidal Au: (a) room temperature (293 K), (b) 423 K, (c) 573 K, (d) 723 K, and (e) 773 K. Dark spots in phase maps and high count zones in fluorescence maps indicate areas most rich in Au. Scale bars = 500 nm.

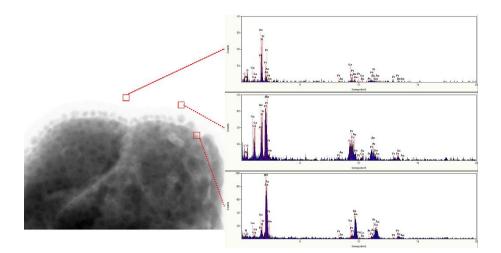


**Figure S10** Depiction of the 2G cell (left) and the temperature profile on the MEMS chip recorded by IR thermography (right). The image was recorded inside the assembled prototype 2G cell during thermal annealing of the colloidal Au sample. Heating was performed via Joule heating principle on only 2 out of 4 pads located on MEMS chips, so the electrical currents could be converted into heat.

#### S6. Electron microscopy analysis of nanoporous gold

Additional high resolution TEM images, EDX analysis and selected area electron diffraction data were recorded on the nanoporous gold sample described in the study. Data was recorded on the sample deposited on a MEMS chip and placed within a Wildfire sample holder (DENSsolutions,

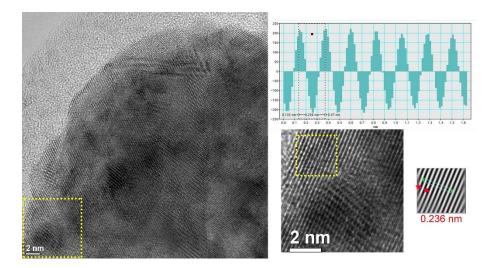
Delft, NL), on a Titan 80-300 (FEI) microscope operated at an acceleration voltage of 300 kV in STEM and TEM mode, at the Institute of Nanotechnology (INT) at Karlsruhe Institute of Technology.



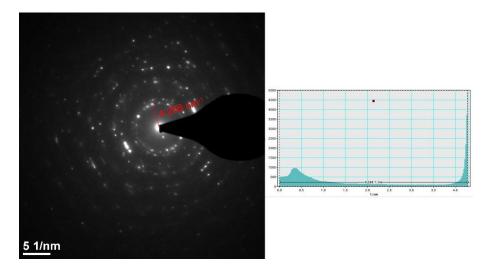
**Figure S11** TEM-EDX data recorded on the nanoporous gold sample used for *in situ* ptychography. Analysis shows the presence of Si and Pt contaminants close to the Au ligament edges.

Element	Atomic %			
	Area 1	Area 2	Area 3	
С	6.2	29.6	29.1	
Ν	6.9	0.0	3.9	
0	5.2	13.1	14.2	
Si	21.3	32.0	52.7	
Ga	0.1	12.1	0.0	
Pt	0.0	10.6	0.0	
Au	60.2	2.6	0.0	

**Table S1**Quantification of EDX spectra in Figure S11.



**Figure S12** Lattice spacing measurement of fresh np-Au sample (highlighted area) via bright-field high resolution TEM, indicating d = 0.236 nm, belonging to (1 1 1) plane of Au metal (PDF 99-0056).



**Figure S13** Lattice spacing measurement of fresh np-Au sample (between indicated points) via selected area electron diffraction, indicating d = 0.234 nm, belonging to (1 1 1) plane of Au metal (PDF 99-0056).